



ECL to TTL Translator (+ 5.0 Vdc Power Supply)

**ELECTRICALLY TESTED PER:
MPG 10H750**

The 10H750 is a member of Motorola's 10H family of high performance ECL logic. It consists of 4 translator with differential inputs and TTL outputs. The 3-state outputs can be disabled by applying a HIGH TTL logic level on the common OE input.

The 10H750 is designed to be used primarily in systems incorporating both ECL and TTL logic operating off a common power supply. The separate V_{CC} power pins are not connected internally and thus isolate the noisy TTL V_{CC} runs from the relatively quiet ECL V_{CC} runs on the printed circuit board. The differential inputs allow the 10H750 to be used as an inverting or non-inverting translator, a differential line receiver or as a high performance comparator.

- Propagation Delay, 3.5 ns Typical
- MECL 10K-Compatible

FUNCTION	PIN ASSIGNMENTS			BURN-IN (CONDITION C)
	DIL	FLATS	LCC	
ECL V _{CC}	1	5	2	V _{CC}
A _{OUT}	2	6	3	GND
A _{IN}	3	7	4	V _{CC}
\overline{A}_{IN}	4	8	5	GND
\overline{B}_{IN}	5	9	7	GND
B _{IN}	6	10	8	V _{CC}
B _{OUT}	7	11	9	GND
GND	8	12	10	GND
\overline{OE}	9	13	12	GND
D _{OUT}	10	14	13	GND
D _{IN}	11	15	14	V _{CC}
\overline{D}_{IN}	12	16	15	GND
\overline{C}_{IN}	13	1	17	GND
C _{IN}	14	2	18	V _{CC}
C _{OUT}	15	3	19	GND
TTL V _{CC}	16	4	20	V _{CC}

BURN - IN CONDITIONS:
V_{CC} = + 6.0 V MAX/ + 5.0 V MIN

Military 10H750

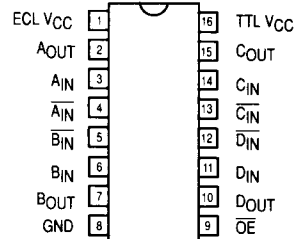


AVAILABLE AS

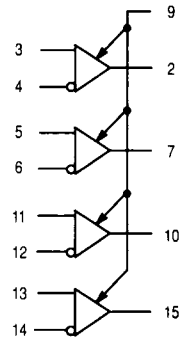
- 1) JAN: N/A
 - 2) SMD: N/A
 - 3) 883: 10H750/BXAJC
- X = CASE OUTLINE AS FOLLOWS:

PACKAGE: CERDIP: E
CERFLAT: F
LCC: 2

The letter "M" appears before the slash on LCC.



LOGIC DIAGRAM



V_{CC} (+ 5.0 V) = Pins 1, and 16
GND = Pin 8

10H750

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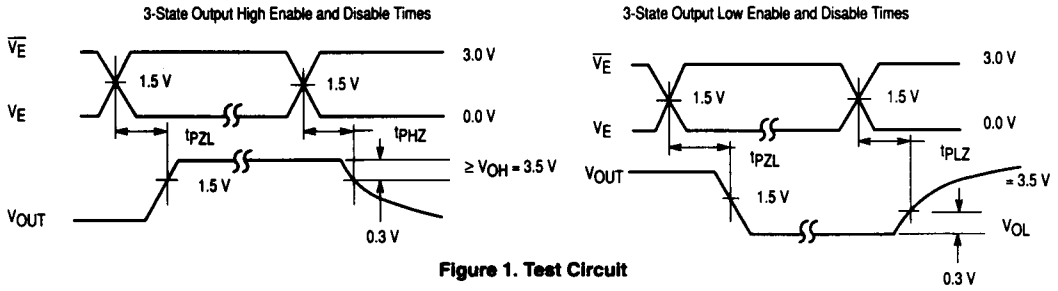


Figure 1. Test Circuit

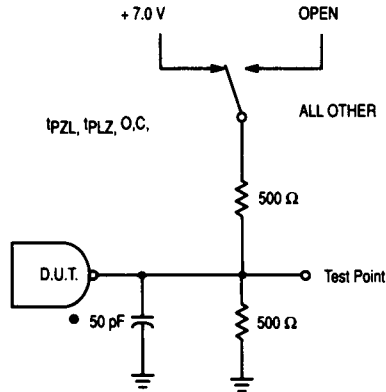


Figure 2. Test Load

• INCLUDES JIG AND PROBE CAPACITANCE

Application Note: Pin 9 is an \overline{OE} and the 10H750 is disabled when \overline{OE} is at V_{IH} or higher

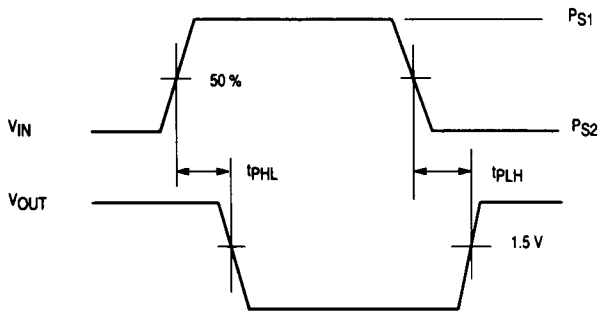


Figure 3. Inverting Waveform Functions

10H750 QUIESCENT LIMIT TABLE *

Test Temperature	Test Voltage Values (Volts) (V _{DIFF} in millivolts)														Test Current (milliAmps)			
	V _{IH1}	V _{IL1}	V _{IH2}	V _{IL2}	PS1	PS2	VCC	VCC1	VCC2	V _{IHH}	V _{ILH}	V _{IHL}	V _{ILL}	V _R	V _{comm.mode}	V _{DIFF}	I _{OH}	I _{OL}
T _A = 25 °C	+2.0	+0.8	+4.2	+3.15	+4.11	+3.31	+5.0	+5.5	+4.5	+5.0	+4.65	+3.15	+2.8	+3.71	+2.8 - +5.0	+350	-3.0	+2.0
T _A = 125 °C	+2.0	+0.8	+4.2	+3.15	+4.22	+3.345	+5.0	+5.5	+4.5	+5.0	+4.65	+3.15	+2.8	+3.82	+2.8 - +5.0	+350	-3.0	+2.0
T _A = -55 °C	+2.0	+0.8	+4.2	+3.15	+4.03	+3.285	+5.0	+5.5	+4.5	+5.0	+4.65	+3.15	+2.8	+3.63	+2.8 - +5.0	+350	-3.0	+2.0

Symbol	Parameter	Limits						Units	TEST VOLTAGE APPLIED TO PINS BELOW									
		+25 °C		+125 °C		-55 °C			Pinouts referenced are for DIL package, check Pin Assignments VCC = 2.0 V, Output Load = 100 Ω to GND									
		Subgroup 9		Subgroup 10		Subgroup 11			V _{I/N}	V _{out}	VCC	V _R	PS1	PS2	P.U.T.			
t _{pd}	Propagation Delay Data	1.5	5.0	1.5	5.2	1.5	5.0	ns	3, 4, 5 11 - 13	2, 7 10, 15	1, 16	3, 4, 5 11 - 13	3 - 6, 9 11 - 14	3 - 6, 9 11 - 14	2, 7, 10, 15			
t _{pdHZ}	Outside Disable Time	2.0	6.0	2.0	6.2	2.0	6.0	ns	3, 4, 5 11 - 13	2, 7 10, 15	1, 16	3, 4, 5 11 - 13	3 - 6, 9 11 - 14	3 - 6, 9 11 - 14	2, 7, 10, 15			
t _{pdHZ}	Outside Disable Time	2.0	6.0	2.0	6.2	2.0	6.0	ns	3, 4, 5 11 - 13	2, 7 10, 15	1, 16	3, 4, 5 11 - 13	3 - 6, 9 11 - 14	3 - 6, 9 11 - 14	2, 7, 10, 15			
t _{pdZL}	Output Enable Time	2.0	8.0	2.0	8.2	2.0	8.0	ns	3, 4, 5 11 - 13	2, 7 10, 15	1, 16	3, 4, 5 11 - 13	3 - 6, 9 11 - 14	3 - 6, 9 11 - 14	2, 7, 10, 15			
t _{pdZH}	Output Enable Time	2.0	8.0	2.0	8.2	2.0	8.0	ns	3, 4, 5 11 - 13	2, 7 10, 15	1, 16	3, 4, 5 11 - 13	3 - 6, 9 11 - 14	3 - 6, 9 11 - 14	2, 7, 10, 15			

* ELECTRICAL CHARACTERISTICS

Each MECL 10H series circuit has been designed to meet the dc specifications shown in the test table, after thermal equilibrium has been established. The circuit is in a test socket or mounted on a printed circuit board and transverse air flow greater than 500 linear fpm is maintained. Outputs are terminated through a 100 Ω resistor to -2.0 volts.

Note

Subgroups A10 and A11, (AC testing) at -55°C and +125°C guaranteed, but not tested.